A Complete Bibliography of Publications in *Technometrics* for the decade 2020–2029

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\$102.12 [Els20]. **\$107.78** [Wlu21]. **\$118.00** [Mal23a]. **\$119.35** [Mye21]. **\$119.99** [Lip20d]. **\$120.00** [Lip23d]. **\$123.83** [Ahm21d]. **\$129.00** [Lip20h, Lip21l]. **\$130.00** [Lip21m, Lip22j, Mal23c]. **\$135** [Nel21]. **\$135.00** [Lip21b]. **\$136.46** [Sau23]. **\$136.93** [Ahm21c]. **\$140.00** [Che22, Lip21h]. **\$152.00** [Lip21g]. **\$160.00** [Lip20a, Lip21c]. **\$174.95** [VL21b]. **\$179.99** [Ahm20a]. **\$185.15** [Zel22]. **\$200.00** [Lip23b]. **\$23.96** [Lip23c]. **\$23.99** [Kha23]. **\$24.95** [Fir23]. **\$25.00** [Mal22a]. **\$28.00** [Lip22b]. 2^5 [Lip21a]. 3 [OKF22, SA23b]. **\$34.00** [Lip23a]. **\$37.99** [Lip20c]. **\$38.00** [Lip22a]. **\$46.36** [Lip21g, Lip21h, Wlu21]. **\$49.99** [Lip22h]. **\$50** [Ano21d]. **\$50.78** [Mal20]. **\$52.49** [Mal23b]. **\$54.95** [Lip22n]. **\$55.96** [Lip22i]. **\$59.96** [Lip21e, Lip21d]. **\$59.98** [Ahm20d]. **\$63.96** [Lip22c, Lip22g]. **\$64.99** [Mal23d]. **\$66.95** [Lip22m]. **\$68** [Mal23e]. **\$69.99** [Lip20f]. **\$74.99** [Ano21b, Lip20e]. **\$75.95** [Lip21f]. **\$76.64** [DM20]. **\$79.95** [Lip20i, Lip22k, Oli20, Wlu23]. **\$79.96** [Lip22e, Lip22l, Lip22f]. **\$83.99** [Ahm21e]. **\$87.20** [Cha22]. **\$87.22** [Lu20].

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Abdalla:2020:BSS

[ABRA20] Nada Abdalla, Sudipto Banerjee, Gurumurthy Ramachandran, and Susan Arnold. Bayesian state space modeling of physical processes in industrial hygiene. *Technometrics*, 62(2):147–160, 2020. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic).

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[Ahm20a] S. Ejaz Ahmed. Book review: *Diagnostic Meta-Analysis: A Useful Tool for Clinical Decision-Making*, by Giuseppe Biondi-Zoccai, (Ed.). Cham, Switzerland: Springer International Publishing, 2018, xii + 319 pp., $179.99, ISBN: 978-3-319-78965-1. *Technometrics*, 62(2):1–289, 2020. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic).

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[Ahm20b] S. Ejaz Ahmed. Book review: *Practical Tools for Designing and Weighting Survey Samples* (2nd ed.), by Richard Valliant, Jill A. Dever, and Frauke Kreuter. Cham, Switzerland: Springer, 2018, x + 776 pp., $99.99, ISBN: 978-3-319-93631-4. *Technometrics*, 62(1): 140, 2020. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic).

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[Ahm21e] S. Ejaz Ahmed. Book review: *Statistical Modeling in Biomedical Research: Contemporary Topics and Voices in the Field*, edited by Yichuan Zhang and Ding-Geng Chen, Switzerland, Springer Nature, 483 pp., $83.99, ISBN: 978-3-030-33415-4. *Technometrics*, 63

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[AL22] Kohma Arai and Vyacheslav Lyubchich. Book review: *Modern Data Science with R* (2nd ed.) by Benjamin S. Baumer, Daniel T. Kaplan, and Nicholas J. Horton, Boca Raton, FL: Chapman and Hall/CRC Press, 2021, 650 pp., $99.95 (Hardback), ISBN: 978-0-367-19149-8. *Technometrics*, 64(3):429, 2022. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic).

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